L Number	Hits	Search Text	DB	Time stamp
1	55	Rinn.in.	USPAT	2004/09/28 20:52
2	5	Rinn.in. with Klaus	USPAT	2004/09/28 20:54
3	288	fricke.in.	USPAT	2004/09/28 20:55
4	0	fricke.in. with wolfgang	USPAT	2004/09/28 20:55
5	43	Wienecke.in.	USPAT	2004/09/28 20:55
6	6	Wienecke.in. with Joachim	USPAT	2004/09/28 20:56

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L Number	Hits	Search Text	DB	Time stamp
-	4199	intensit$4 near2 profile	USPAT	2004/09/28 13:03
-	560	(intensit$4 near2 profile) same edge	USPAT	2004/09/28 13:04
-	4	(intensit$4 near2 profile) same (model with edge)	USPAT	2004/09/28 13:05
-	36	(intensit$4 near2 profile) with nonlinear	USPAT	2004/09/28 13:27
-	543	one near2 dimension$4 near2 edge	USPAT	2004/09/28 13:45
-	7	(one near2 dimension$4 near2 edge) same model	USPAT	2004/09/28 13:41
-	39	(one near2 dimension$4 near2 edge) with (detect$4 or recogn$6)	USPAT	2004/09/28 13:57
-	19116	(edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))	USPAT	2004/09/28 14:00
-	552	((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same profile	USPAT	2004/09/28 14:00
-	191	((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same model	USPAT	2004/09/28 14:02
-	6438	((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location)	USPAT	2004/09/28 14:07
-	3185	(((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location)) and (wafer or semiconduct$3 or model or table or stage)	USPAT	2004/09/28 14:06
-	1367	((((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location)) and (wafer or semiconduct$3 or model or table or stage)) and (pixel or intensit$3)	USPAT	2004/09/28 14:06
-	680	((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location) same (pixel or intensit$4)	USPAT	2004/09/28 14:08
-	562	((((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location)) and (wafer or semiconduct$3 or model or table or stage)) and (((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location) same (pixel or intensit$4))	USPAT	2004/09/28 14:11
-	225	(((edge or boundar$3 or contour or perimeter) near2 (mask or window or (one adj1 dimension$3))) same (detect$4 or recogn$6 or position or location) same (pixel or intensit$4)) and camera	USPAT	2004/09/28 14:11

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Shi, Y.Q.; Zhou, S.F.;
Circuits and Systems, 1991., IEEE International Sympoisum on , 11-14 June
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[Abstract]   [PDF Full-Text (312 KB)]   **IEEE CNF**

2 **The WMMR filters: a class of robust edge enhancers**
Longbotham, H.; Eberly, D.;
Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Sigi
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Pages:1680 - 1685

[Abstract]   [PDF Full-Text (648 KB)]   **IEEE JNL**

3 **Performance enhancement in acousto-optic image processing**
Banejee, P.P.; Cao, D.; Poon, T.-C.;
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4 **A simple technique to evaluate winding losses including two dimen:
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Kutkut, N.H.;
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Yamada, T.;
Communications, IEEE Transactions on [legacy, pre - 1988] , Volume: 27 , Is 8 , Aug 1979
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[Abstract]   [PDF Full-Text (864 KB)]   **IEEE JNL**

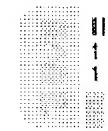2 **Model building of three-dimensional polyhedral objects using 3D ed information and hemispheric histogram**
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3 **Stability analysis of M-dimensional asynchronous swarms with a fix communication topology**
Yang Liu; Passino, K.M.; Polycarpou, M.M.;
Automatic Control, IEEE Transactions on , Volume: 48 , Issue: 1 , Jan. 2003
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4 **Multiple-source localization using GPS technology and received arri time structure analysis in an air-deployed system**
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Toeltsch, M.; Laurila, J.; Kalliola, K.; Molisch, A.F.; Vainikainen, P.; Bonek, E.
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